EMC TEST REPORT

Equipment	USB 2.0 Hub, USB A male to 4 x USB A female
Trade mark	
Model No.	COM610
Report No.	CTB210428021EX
Applicant	FullStrike.LTD
	Room 2801, International Technology Building, ShenNan Road, Futian district, SZ,518033 PRC
Manufacturer	FullStrike.LTD
	No. 123 Building A, Investment & Venture Center, Jinhui West Road, Yinzhou Dist., Ningbo City, Zhejiang Provice, China
Prepared by	Shenzhen CTB Testing Technology Co., Ltd.
	Floor 1&2, Building A, No. 26 of Xinhe Road, Xinqiao Street, Baoan District, Shenzhen China Tel: 4008-707-283 Fax: 086-0755-23208027
Date of Receipt	Apr. 25, 2021
Date of Test(s)	Apr. 25, 2021 ~ Apr. 28, 2021
Date of Issue	Apr. 28, 2021
Test Standard(s)	EN 55032:2015, EN 55035:2017/A11:2020
In the configuration	on tested, the EUT complied with the standards specified above.
Producer :	Lisa Deng/ Engineer , Date :
Signatory :	, Date :
	Bin Mei/ Director

Note: The results shown in this test report refer only to the sample(s) tested unless otherwise stated. This test report shall not be reproduced except in full, without prior written approval of CTB. This document may be altered or revised by CTB, personnel only, and shall be noted in the revision of the document.



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Revision History

Edition No. Date of Revision Revision Summary Report Number 0 Apr. 28, 2021 Original Report CTB210428021EX		<u>~ ~ ~ ~ ~</u>	Revision History	
	Edition No.	Date of Revision	Revision Summary	Report Number
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1. TEST SUMMARY

	Emission		
Requirement - Test	Test Method	Limit	Result
Conducted Emission		Class B	N/A
Radiated emissions at frequencies up to 1 GHz	EN 55032:2015	Class B	PASS
Radiated emissions at frequencies above 1 GHz		Class B	N/A
Harmonic current emissions	EN IEC 61000-3-2:2019	Class A	N/A
Voltage changes, voltage fluctuations and flicker	EN 61000-3-3:2013/A1:2019	Clause 5	N/A
Imm	unity (EN 55035:2017/A11:2020)	•	
Requirement - Test	Test Method	Performance criteria	Result
Electrostatic discharges (ESD)	EN 61000-4-2:2009	В	PASS
Electromagnetic field	EN 61000-4-3: 2006+A1:2008+A2:2010	A	PASS
Electrical fast transients/burst (EFT/B)	EN 61000-4-4:2004+A1:2010	B	N/A
Surges	EN 61000-4-5:2006	В	N/A
Conducted RF	EN 61000-4-6:2009	A	N/A
Power frequency magnetic field	EN 61000-4-8:2010	A	N/A
Voltage dips and Short interruptions	EN 61000-4-11:2009+A1:2010	B & C	N/A

Remark: N/A is abbreviation for Not Applicable.

The test was carried out in all the test modes, only the worst data are list in report.



2. GENERAL INFORMATION

2.1. Description of EUT

Equipment	USB 2.0 Hub, USB A male to 4 x USB A female
Trade mark	
Model Name	COM610
Serial No.	
Model Difference	All model's the function, software and electric circuit are the same, only with a product color and model named different.
	Test sample model: COM610.
Rated Power Supply	DC 12V from PC
Rated Power	
Normal Testing Voltage	DC 12V from PC
Configuration	🛛 Table-top 🗌 Floor-standing
Accessory Device	Notebook+ display
Cable Supplied	USB cable ,

Note:

1. Other Accessory Device List and Details

Description	Manufacturer	Model	Note

External I/O Cable

Cable Description	Shielded Type	Ferrite Core	Length(m)	Note
	Shielded Non-shielded	□Yes □No		
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2. The above EUT information is declared by manufacturer and for more detailed features description, please refer to the manufacturer's specifications or the User's Manual.



2.2. Operating condition of EUT

To investigate the maximum EMI emission characteristics generates from EUT, the test system was pre-scanning tested base on the consideration of following EUT operation mode or test configuration mode which possible have effect on EMI emission level. Each of these EUT operation mode(s) or test configuration mode(s) mentioned above was evaluated respectively

Pretest Mode	Description
Mode 1	Working

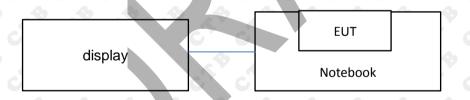
For Conducted Test				
Final Test Mode	Description			
Mode 1	Working			
Mode 2	charge			

	For Radiated Test				
Final Test Mode	Description				
Mode 1	Working				
Mode 2	charge				

2.3. Test conditions

Temperature: 15-35°C Relative Humidity: 30-60 % Atmospheric pressure: 800hPa-1060hPa

2.4. Block diagram of EUT configuration





3. FACILITIES

3.1. Test Facility

CTB-LAB

Floor 1&2, Building A, No. 26 of Xinhe Road, Xinqiao Street, Baoan District, Shenzhen China

3.2. Test Instruments

Radiated Emission Measurement (Test software: EZ-EMC Ver. FA-03A2 RE)

Item	Equipment	Manufacturer	Model No.	Serial No.	Calibrated until
1	Double Ridged Broadband Horn Antenna	Schwarzbeck	BBHA 9120D	1911	2021.11.02
2	TRILOG Broadband Antenna	Schwarzbeck	VULB 9168	869	2021.11.02
3	Amplifier	Agilent	8449B	3008A01838	2021.11.01
4	Amplifier	CHPC C	8447E	2945A02747	2021.11.01
5	EMI TEST RECEIVER	ROHDE&SCHWARZ	ESPI7	100362	2021.11.01
6	Coaxial cable	ETS	RFC-SNS- 100-NMS-80 NI		2021.11.01
7	Coaxial cable	ETS	RFC-SNS- 100-NMS-20 NI		2021.11.01
8	Coaxial cable	ETS	RFC-SNS- 100-SMS-20 NI		2021.11.01
9	Coaxial cable	ETS	RFC-NNS- 100-NMS- 300 NI		2021.11.01

Electrostatic Discharge Test

Item	Equipment	Manufacturer	Model No.	Serial No.	Calibrated until
1	ESD Simulator	TESTQ	NSG437	329	2021.10.30

RF electromagnetic field Test

Item	Equipment	Manufacturer	Type No.	Serial No.	Calibrated until
1	Signal Generator	Agilent	N5182A	MY47420195	2021.10.30
2	Log-Bicon Antenna	Schwarzbeck	VULB9161	9128ES-128	2021.10.30
3	Power Amplifier	AR	150W1000M1	342526	2021.10.30
4	Microwave Horn Antenna	AR	AT4002A	322279	2021.10.30
5	Power Amplifier	AR	25S1G4A	321116	2021.10.30

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4. Measurement uncertainty

The following table is for the measurement uncertainty, which is calculated as per the document CISPR 16-4.

Test	Parameters	Expanded Uncertainty (U _{Lab})	Expanded Uncertainty (U _{Cispr})
Conducted Emission	Level Accuracy: 150kHz to 30MHz	±1.22 dB	±3.6 dB
Radiated Emission	Level Accuracy: 30MHz to 1000 MHz	±3.67 dB	±5.2 dB
Radiated Emission	Level Accuracy: Above 1000MHz	±4.79 dB	N/A

This uncertainty represents an expanded uncertainty expressed at approximately the 95% confidence level using a coverage factor of k=2.



5. Emission

5.1.Conducted Emission

5.1.1. Limit

Requirements for conducted emissions from the AC mains power ports of Class A equipment

Frequency range MHz	Coupling device	Detector type / bandwidth	Class A limits dB(µV)
0,15 to 0,5		Quesi Beek / 0 kl la	79
0,5 to 30	AMN	Quasi Peak / 9 kHz	73
0,15 to 0,5	AIVIN		66
0,5 to 30	1 × × × ×	Average / 9 kHz	60

Requirements for conducted emissions from the AC mains power ports of Class B equipment

Frequency range MHz	Coupling device	Detector type / bandwidth	Class B limits dB(µV)
0,15 to 0,5	x x x x	KY KY KY	66 to 56
0,5 to 5		Quasi Peak / 9 kHz	56 0
5 to 30	AMN	b 4b 4b 4b	60
0,15 to 0,5	Aivin	S . S . S	56 to 46
0,5 to 5	000	Average / 9 kHz	46
5 to 30			50

Requirements for asymmetric mode conducted emissions from Class A equipment

Frequency range MHz	Coupling device	Detector type / bandwidth	Class A limits dB(µV)
0,15 to 0,5	29 29 X	Oussi Desk / Okt Iz	97 to 87
0,5 to 30	AAN	Quasi Peak / 9 kHz	87
0,15 to 0,5	AAN		84 to 74
0,5 to 30		Average / 9 kHz	74

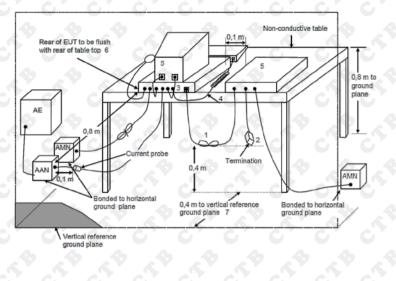
Requirements for asymmetric mode conducted emissions from Class B equipment

Frequency range MHz	Coupling device	Detector type / bandwidth	Class B limits dB(µV)
0,15 to 0,5 0,5 to 30		Quasi Peak / 9 kHz	84 to 74 74
0,15 to 0,5 0,5 to 30	AAN	Average / 9 kHz	74 to 64 64

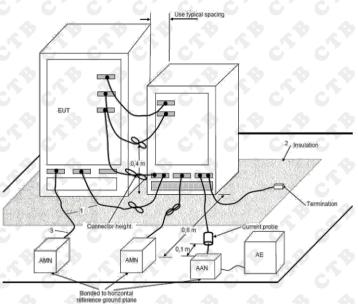


5.1.2. Test setup

For table-top equipment



For floor standing equipment



5.1.3. Test procedure

Measurement was performed in shielded room, and instruments used were followed CISPR 16-2-1 clause7.

Detailed test procedure was following clause 7 of CISPR 16-2-1.

Frequency range 150kHz – 30MHz was checked and EMI receiver measurement bandwidth was set to 9 kHz.

5.1.4. Test results

N/A



5.2. Radiated emissions

5.2.1. Limit

Requirements for radiated emissions at frequencies up to 1 GHz for class A equipment

Frequency		Class P limite			
range MHz	Facility Distance m		Detector type / bandwidth	Class B limits dB(µV/m)	
30 to 230	SAC	j O	Quasi Peak /	50 0	
230 to 1 000	SAC		120 kHz	57	

Requirements for radiated emissions at frequencies above 1 GHz for class A equipment

Frequency		Class B limits		
range	Facility	Distance	Detector type /	
MHz	Facility	m	bandwidth	dB(µV/m)
1 000 to 3 000	C C	С С	Average /	56 0
3 000 to 6 000	FSOATS	\mathbf{A}	1MHz	60
1 000 to 3 000	FSUATS		Average /	76
3 000 to 6 000		3	1MHz	80

Requirements for radiated emissions at frequencies up to 1 GHz for class B equipment

2	Frequency		Class B limits			
5	range MHz	Facility	Distance m	Detector type / bandwidth	dB(µV/m)	
-	30 to 230 230 to 1 000	SAC	3	Quasi Peak / 120 kHz	40 47	

Requirements for radiated emissions at frequencies above 1 GHz for class B equipment

Frequency		Class B limits		
range MHz	Facility	Distance m	Detector type / bandwidth	dB(µV/m)
1 000 to 3 000		2	Average /	50
3 000 to 6 000	FROATO	3	1MHz	54
1 000 to 3 000	FSOATS		Average /	70
3 000 to 6 000		3	1MHz	74



5.2.2. Block diagram of test setup

Measurement distance Turntable Test table Reference point of antenna calibration Boundary of EUT (imaginary circular periphery) AE/ EUT EUT Measurement distance For table-top equipment For floor standing equipment 0,1 m Non-conductive support 0,1 m Typical spacing Æ EUT/AE EUT/AE PSU EUT/AE ypical spacing EUT/AE EUT/AE 0,2 m To AE TO AE 0.4 m Insulation Insulation



5.2.3. Test procedure

The measurement was performed in a semi-anechoic chamber. The distance from EUT to receiving antenna is 3 meters. Measurement was performed according to clause 7.3 of CISPR 16-2-3.

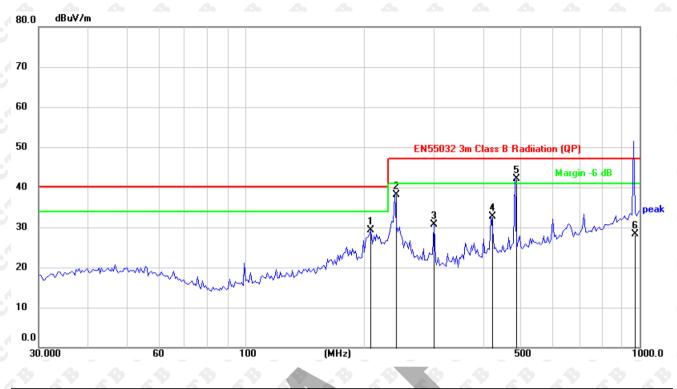
5.2.4. Test results

PASS

Please refer to the following page.



Polarization: H



No.	Mk.	Freq.	Reading Level	Correct Factor	Measure- ment	Limit	Over		Antenna Height	Table Degree	
		MHz	dBuV	dB	dBuV/m	dB/m	dB	Detector	cm	degree	Comment
1	2	208.2148	39.47	-10.08	29.39	40.00	-10.61	QP			
2	2	239.5670	47.14	-8.99	38. <mark>1</mark> 5	47.00	-8.85	QP			
3	÷	300.8943	37.46	-6.79	30.67	47.00	-16.33	QP			
4	4	419.8436	36.87	-4.22	32.65	47.00	-14.35	QP			
5	* 4	483.0618	44.91	-2.84	42.07	47.00	-4.93	QP			
6	Ş	965.5921	21.67	6.72	28.39	47.00	-18.61	QP	100	360	

Note: Result=Reading+Factor Over Limit=Result-Limit



Polarization: V



No.	Mk	. Freq.	Reading Level	Correct Factor	Measure- ment	Limit	Over		Antenna Height	Table Degree	
		MHz	dBuV	dB	dBuV/m	dB/m	dB	Detector	cm	degree	Comment
1	*	177.8207	43.12	-8.44	34.68	40.00	-5.32	QP			
2	İ	239.5669	50.22	-8.99	41.23	47.00	-5.77	QP			
3		263.8190	47.18	-8.11	39.07	47.00	-7.93	QP			
4		401.8385	44.38	-4.62	39.76	47.00	-7.24	QP			
5		483.0617	40.25	-2.84	37.41	47.00	-9.59	QP			
6		965.1421	23.01	6.72	29.73	47.00	-17.27	QP	100	360	

Note: Result=Reading+Factor Over Limit=Result-Limit



5.3. Harmonic current emissions

5.3.1. Test Setup

Harmonic & flicker test system EUT

5.3.2. Test Procedure

Basic Standard(s) Measurement Equipment requirement Measured Harmonics Equipment Class Limits

- EN IEC 61000-3-2:2019
- IEC 61000-4-7
- : 1 40
- Clause 7.1 Table 1
- Clause 7.2
- Clause 7.3 Table 2
- Clause 7.4 Table 3
- ☐ This product is not defined as lighting equipment, and has rated power less than 75W, therefore, no limit applies according to EN 61000-3-2
- ☐ The EUT is kitchen machines as listed in the scope of IEC 60335-2-14, therefore, is deemed to conform to the harmonic current limits of this standard without further testing.

5.3.3. Test Result

N/A

No adapters ,EUT not applicable to this test.



5.4. Voltage changes, voltage fluctuations and flicker

5.4.1. Test Setup

Harmonic & flicker test system



5.4.2. Test Procedure

Limits

Basic Standard(s)

Measurement Equipment requirement

EN 61000-3-3:2013/A1:2019

- IEC 61000-4-15
- Clause 5

5.4.2.1 Definition

Flicker: impression of unsteadiness of visual sensation induced by a lighting stimulus whose luminance or spectral distribution fluctuates with time.

Pst: Short-term flicker indicator the flicker severity evaluated over a short period (in minutes);

Pst=1 is the conventional threshold of irritability

P_{it}: long-term flicker indicator; the flicker severity evaluated over a long period (a few hours) using successive P_{st} values.

dc: the relative steady-state voltage change

- d_{max}: the maximum relative voltage change
- d(t): the value during a voltage change

5.4.2.2 Test Precedure

The following limits apply

- -- "P_{lt}" shall not exceed 0.65.
- -- "Pst" shall not exceed 1.0.
- -- "dc" shall not exceed 3.3%.
- -- "d(t)" shall not exceed 3.3% for more than 500ms.
- -- "d_{max}" shall not exceed:
 - 4% without additional conditions,
 - 6% switched manually or automatically more than twice per day,
 - ☐ 7% attended whilst in use or switched automatically for no more than twice per day or attended while in use.
 - ☐ For manual switch, dmax is measured in accordance with Annex B of standard, average dmax is calculated from 24 times measurement.
 - ☐ The EUT is unlikely to produce significant voltage fluctuations or flicker by technical analysis and evaluation. So it is deemed to fulfil the requirements without testing.

5.4.3. Test Result

N/A

No adapters ,EUT not applicable to this test.



6. Immunity

Performance criteria

Performance criterion A

The equipment shall continue to operate as intended without operator intervention. No degradation of performance or loss function is allowed below a performance level specified by the manufacturer, when the equipment is used as intended. The performance level may be replaced by a permissible loss of performance. If the minimum performance level or the permissible performance loss is not specified by the manufacturer, then either of these may be derived from the product description and documentation, and by what the user may reasonably expect from the equipment if used as intended.

Performance criterion B

The equipment shall continue to operate as intended after the test. No degradation of performance or loss function is allowed below a performance level specified by the manufacturer, when the equipment is used as intended. During the test, degradation of performance is however allowed. No change of actual operating state or stored data is allowed. If the minimum performance level or the permissible performance loss is specified by the manufacturer, either of these may be derived from the product description and documentation and what the user may reasonably expect from equipment if used as intended.

Performance criterion **C**

Temporary loss of function is allowed, provided the function is self-recoverable or can be restored by operation of the controls.



6.1. Electrostatic discharges (ESD)

6.1.1. Test Levels and Performance Criterion

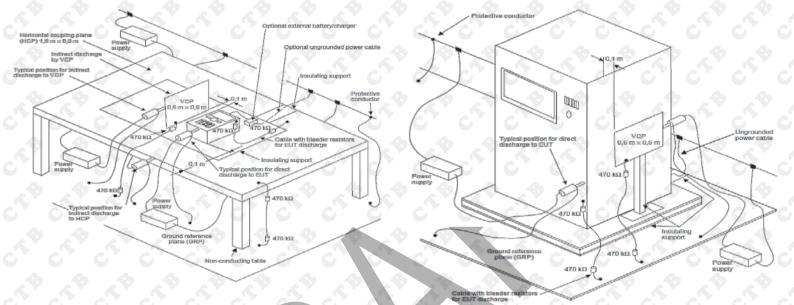
Characteristics	Test levels
Air discharge	±8 kV
Contact discharge	±4 kV

Performance criterion: B

6.1.2. Test setup

For table-top equipment

For floor standing equipment



6.1.3. Test Procedure

Measurement was performed in shielded room. Measurement procedure was applied according to EN 61000-4-2 clause 8. The test method and equipment were specified by EN 61000-4-2.

6.1.4. Test Result

PASS

Please refer to the following page.

	P&N	СС	10		
			10	40	PASS
2 VCP		С	10	4	PASS
3 Points on conductive surface		С	10	4	PASS
4 Points on non-conductive surface		A	10	8	PASS
	s on non-conductive surface	s on non-conductive surface P&N ontal coupling plate VCP = Vertical coupl	s on non-conductive surface P&N A ontal coupling plate VCP = Vertical coupling plate N	s on non-conductive surface P&N A 10 ontal coupling plate VCP = Vertical coupling plate N = Negative	s on non-conductive surface P&N A 10 8 ontal coupling plate VCP = Vertical coupling plate N = Negative P = Positive



6.2. Electromagnetic field

6.2.1. Test Levels and Performance Criterion

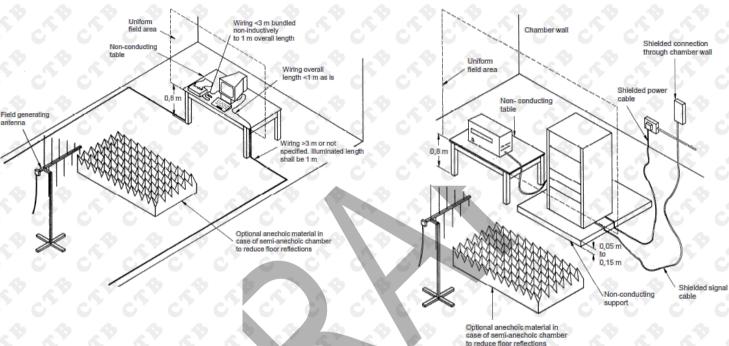
Characteristics	Test levels	Test levels
Frequency range	80 MHz to 1 000 MHz,	1 800MHz, 2 600MHz,
& & &	6 6 6 6 6 6	3 500MHz, 5 000MHz
Test level	3 V/m (unmodulated)	3 V/m (unmodulated)
Modulation	1 kHz, 80 % AM, sine wave	1 kHz, 80 % AM, sine wave

Performance criterion: A

6.2.2. Test setup

For table-top equipment





6.2.3. Test Procedure

Measurement was performed in full-anechoic chamber. Measurement procedure was applied according to EN 61000-4-3 clause 8. The test method and equipment was specified by EN 61000-4-3.

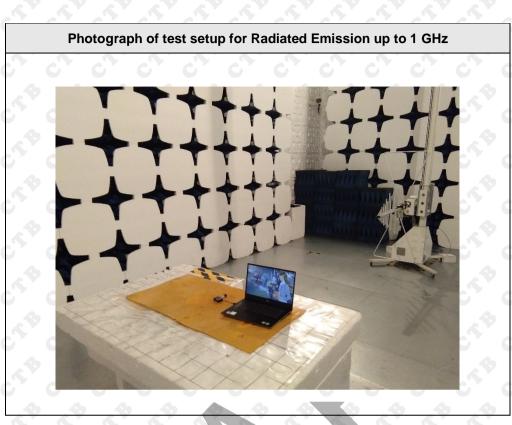
6.2.4. Test Result

PASS

Enclosure	Horizontal	Vertical
Front	PASS	PASS
Right Side	PASS	PASS
Left Side	PASS	PASS
Rear	PASS	PASS



7. Photographs of test setup





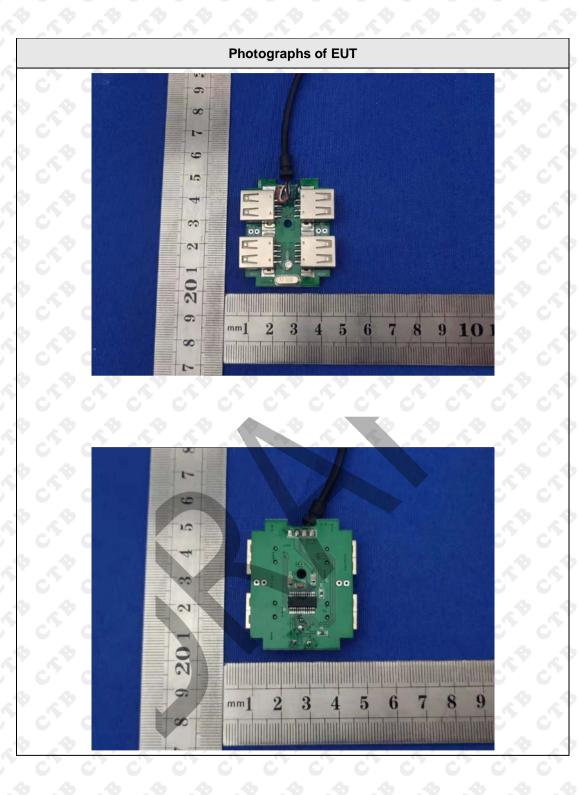
8. Photographs of EUT











End of report